

United States Patent and Trademark Office

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILIN	NG DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/699,256	10/699,256 10/30/2003 Chih-Chen Cho 27076 7590 04/21/2006		Chih-Chen Cho	500982.02 (30016/US/2)	9603
27076			EXAMINER		
DORSEY	& WHITNE	Y LLP	THOMAS, TONIAE M		
INTELLEC SUITE 340		PERTY DEPARTN	ART UNIT	PAPER NUMBER	
	I AVENUE		2822	2822	
SEATTLE,	WA 98101		DATE MAILED: 04/21/2006		

Please find below and/or attached an Office communication concerning this application or proceeding.

		•	· 11 /					
		Application No.	Applicant(s)					
		10/699,256	CHO ET AL.					
	Office Action Summary	Examiner	Art Unit					
		Toniae M. Thomas	2822					
Pei	The MAILING DATE of this communication appriod for Reply	ears on the cover sheet with the	correspondence address					
	A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING DA - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION B6(a). In no event, however, may a reply be tile rill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	N. mely filed the mailing date of this communication. ED (35 U.S.C. § 133).					
Sta	itus	•	* *					
	1)⊠ Responsive to communication(s) filed on 27 Fe	ebruary 2006.						
2	2a) This action is FINAL . 2b) ☑ This							
•	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is							
	closed in accordance with the practice under E	x parte Quayle, 1935 C.D. 11, 4	53 O.G. 213.					
Dis	position of Claims		•					
	4) ⊠ Claim(s) 1-18,32,34-37 and 44 is/are pending in 4a) Of the above claim(s) is/are withdraw 5) ⊠ Claim(s) 1-18,32 and 34-37 is/are allowed. 6) ⊠ Claim(s) 44 is/are rejected. 7) □ Claim(s) is/are objected to. 8) □ Claim(s) are subject to restriction and/or	vn from consideration.						
Δр	plication Papers							
	9) The specification is objected to by the Examiner	r.						
	10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner.							
	Applicant may not request that any objection to the	drawing(s) be held in abeyance. Se	e 37 CFR _. 1.85(a).					
	Replacement drawing sheet(s) including the correcti	, •	• • • • • • • • • • • • • • • • • • • •					
•	11)☐ The oath or declaration is objected to by the Ex	aminer. Note the attached Office	Action or form PTO-152.					
Pri	ority under 35 U.S.C. § 119	•	•					
•	12) Acknowledgment is made of a claim for foreign	priority under 35 U.S.C. § 119(a)-(d) or (f).					
	a) ☐ All b) ☐ Some * c) ☐ None of:							
	1. Certified copies of the priority documents have been received.							
	2. Certified copies of the priority documents	• •	•					
•	3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).							
	* See the attached detailed Office action for a list of	, , , ,	ed .					
	250 mg anasinsa asianoa omoc action for a list (or and dominou dopies not receive	Ju.					
		•						
			•					
_	chment(s) Notice of References Cited (PTO-892)	41 M 1-4 10 0 0 0 0	· (DTO 442)					
2) E	☐ Notice of Preferences Cited (P10-892) ☐ Notice of Draftsperson's Patent Drawing Review (PT0-948)	4) 🔀 Interview Summary Paper No(s)/Mail D						
3) [Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date		Patent Application (PTO-152)					
			_					

Application/Control Number: 10/699,256

Art Unit: 2822

DETAILED ACTION

Page 2

1. This Office action is responsive to the amendment filed on 27 February 2006.

- 2. Currently, claims 1-18, 32, 34-37, and 44 are pending.
- 3. The indicated allowability of claim 44 is withdrawn in view of the reference to Cho et al. (US 6,730,553 B2). A rejection based on the Cho et al. reference follows.

Double Patenting

4. The nonstatutory double patenting rejection is based on a judicially created doctrine grounded in public policy (a policy reflected in the statute) so as to prevent the unjustified or improper timewise extension of the "right to exclude" granted by a patent and to prevent possible harassment by multiple assignees. A nonstatutory obviousness-type double patenting rejection is appropriate where the conflicting claims are not identical, but at least one examined application claim is not patentably distinct from the reference claim(s) because the examined application claim is either anticipated by, or would have been obvious over, the reference claim(s). See, e.g., *In re Berg*, 140 F.3d 1428, 46 USPQ2d 1226 (Fed. Cir. 1998); *In re Goodman*, 11 F.3d 1046, 29 USPQ2d 2010 (Fed. Cir. 1993); *In re Longi*, 759 F.2d 887, 225 USPQ 645 (Fed. Cir. 1985); *In re Van Ornum*, 686 F.2d 937, 214 USPQ 761 (CCPA 1982); *In re Vogel*, 422 F.2d 438, 164 USPQ 619 (CCPA 1970); and *In re Thorington*, 418 F.2d 528, 163 USPQ 644 (CCPA 1969).

A timely filed terminal disclaimer in compliance with 37 CFR 1.321(c) or 1.321(d) may be used to overcome an actual or provisional rejection based on a nonstatutory double patenting ground provided the conflicting application or patent either is shown to be commonly owned with this application, or claims an invention made as a result of activities undertaken within the scope of a joint research agreement.

Effective January 1, 1994, a registered attorney or agent of record may sign a terminal disclaimer. A terminal disclaimer signed by the assignee must fully comply with 37 CFR 3.73(b).

5. Claim 44 is rejected on the ground of nonstatutory obviousness-type double patenting as being unpatentable over claim 2 of U.S. Patent No.

Application/Control Number: 10/699,256

Art Unit: 2822

6,730,553. Although the conflicting claims are not identical, they are not patentably distinct from each other because claim 44 recites the following limitations as recited in the patented claim: forming from a nonconductive stack a number of openings to expose a number of semiconductor structures in the array area and in the periphery area, the nonconductive stack including a stopping layer to stop an etching process once etched away to define the bottom of each opening; exposing a portion of a polycrystalline silicon layer in the array area; and filling the number of openings with a conductive stack having the characteristic to reduce a vertical resistance of each semiconductor structure and a horizontal resistance of each semiconductor structure so as to increase the performance of each semiconductor structure.

Page 3

Reasons for Allowance

6. The following is an examiner's statement of reasons for allowance: the prior art of record does not anticipate, teach or suggest a method for making a semiconductor structure in a substrate having an array area and periphery¹ substantially as claimed, wherein the method comprises at least the steps of: depositing a nonconductive stack over a transistor in the array area and a transistor in the periphery area, the nonconductive stack comprising a stopping layer and a nonconductive layer, respectively; and etching openings by etching the nonconductive stack in at least the array area to expose a

¹ The term "periphery" as used herein is interpreted to mean the peripheral circuitry region of a memory device (see specification page 5, lines 24-27). Likewise, the term "array" as used

Art Unit: 2822

polycrystalline silicon layer of the transistor in the array area, as recited in claim 1. Secondly, the prior art of record does not anticipate, teach or suggest a method for making a semiconductor structure in a semiconductor substrate having an array area and periphery substantially as claimed, wherein the method comprises at least the steps of: depositing a nonconductive stack over a gate and source/drain of a memory cell in the array area and over a gate of a transistor in the periphery area, the nonconductive stack comprising a stopping layer and a nonconductive layer, respectively; and removing portions in at least the array that are marked by photolithography to expose a polycrystalline silicon layer of the gate of the memory cell in the array area, as recited in claim 6. Thirdly, the prior art of record does not anticipate, teach or suggest a method for making a semiconductor structure in a substrate having an array area and periphery substantially as claimed, wherein the method comprises at least the steps of: depositing a nonconductive stack having a stopping layer over gates in the array and in the periphery area; and dry etching portions of the array and the periphery until stopped by the stopping layer to expose a portion of the polycrystalline silicon layer of at least one of the gates in the array area and the periphery, as recited in claim 11. Lastly, the prior art of record does not anticipate, teach or suggest a method for forming a routing in a periphery area of a semiconductor structure substantially as claimed, the method comprising forming from a nonconductive stack a trench

that superjacently abuts a second gate stack including a polycrystalline silicon layer in the periphery, wherein the nonconductive stack includes a stopping layer that stops an etch process once etched away to define the bottom of the trench and expose at least a portion of the polycrystalline silicon layer of the second gate stack, as recited in claim 32.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Toniae M. Thomas whose telephone number is (571) 272-1846. The examiner can normally be reached on Monday through Friday from 8:30 a.m. to 5:30 p.m.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Zandra Smith can be reached on (571) 272-2429. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

TMT 17 April 2006

Mary Wilczewski Primary Examiner